Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/693,885	LEE ET AL.	
Examiner	Art Unit	
B. Clayton McCraw	3744	

SEARCHED				
Class	Subclass	Date	Examiner	
62	176.1, 176.6, 331, 160	2/9/2006	ВСМ	
236	44A, 44C	2/9/2006	всм	
62	176.1	8/20/2006	всм	
62	176.6,160	8/20/2006	ВСМ	
62	331	8/20/2006	ВСМ	
236	44A, 44C	8/20/2006	всм	

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
See 4H	adied	8/20/06	BCM		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Consulted with Primary Examiner, Marc Norman	2/9/2006	всм		
Conducted Inventor Name Search	2/9/2006	всм		
EAST Search Notes Attached	2/16/2006	всм		
EAST Search Notes Attached	8/20/2006	всм		
EAST Interference Search Attached	8/20/2006	всм		